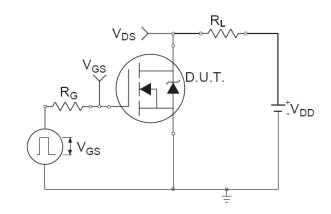
Features

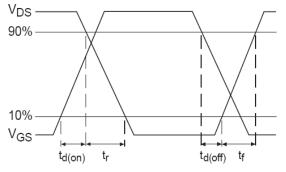
- V_{DSS} =100V/ V_{GSS} =±25V/ I_{D} =140A $R_{DS(ON)}$ =7.2m Ω (max.)@ V_{GS} =10V
- Low Dense Cell Design
- Reliable and Rugged
- Advanced trench process technology

Applications

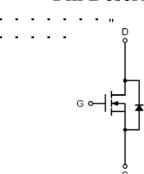
- Synchronous Rectification
- Power Management in Inverter System

Switching Time Test Circuit and Waveforms





Pin Description





Marking and pin Assignment



TO-220-3L top view

Package Marking and Ordering Information

Device Marki	ng Device	Device Packa	ge Ree	el Size	Tape width	Quantity	
PTIHF€	PTIHF€	ÆÁVUË3€EËHŠ	/ ////////////////////////////////////	((i∷ /)(((((i)((((((((((((((((((((((((((((((}	/////////////////////////////////////	ÁÁÁ

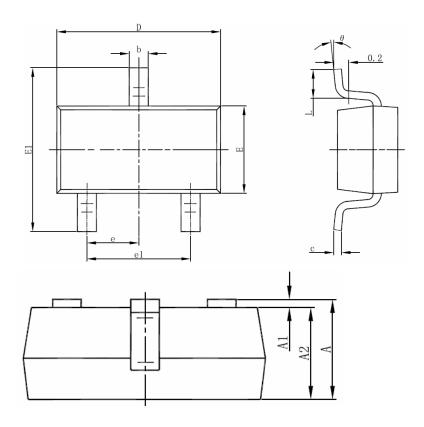
Electrical Characteristics of CP Test (TA=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур	Max.	Unit
Static Char	acteristics					
BV_{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V,I _D =250uA	100			V
Ţ	Zero Gate Voltage Drain Current	$V_{DS} = 80V, V_{GS} = 0V$			1	A
I_{DSS}		T _J =85°C			30	uA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250$ uA	2	2.8	4	V
I_{GSS}	Gate Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$			±100	nA
R _{DS(on)}	Drain-Source On-Resistance	V _{GS} =10V, I _D =40A		6.2	7.2	mΩ
V_{SD}	Diode Forward Voltage	I_{SD} =30A, V_{GS} =0V			1.3	V
R_{G}	Gate Resistance	V _{GS} =0V, V _{DS} =0V, Frequency=1MHz		1.7		Ω

Note: 1: Pulse test; pulse width ≤ 300 ns, duty cycle $\leq 2\%$.

^{2:} Guaranteed by design, not subject to production testing.

SOT-23-3L PACKAGE INFORMATION



Symbol	Dimensions In	Millimeters	Dimensions In Inches		
	Min	Max	Min	Max	
Α	1.050	1.250	0.041	0.049	
A1	0.000	0.100	0.000	0.004	
A2	1.050	1.150	0.041	0.045	
b	0.300	0.500	0.012	0.020	
С	0.100	0.200	0.004	0.008	
D	2.820	3.020	0.111	0.119	
E	1.500	1.700	0.059	0.067	
E1	2.650	2.950	0.104	0.116	
е	0.950	(BSC)	0.037(BSC)		
e1	1.800	2.000	0.071	0.079	
Ĺ	0.300	0.600	0.012	0.024	
θ	0°	8°	0°	8°	

NOTES

- 1. All dimensions are in millimeters.
- 2. Tolerance ±0.10mm (4 mil) unless otherwise specified
- $3.\ Package\ body\ sizes\ exclude\ mold\ flash\ and\ gate\ burrs.\ Mold\ flash\ at\ the\ non-lead\ sides\ should\ be\ less\ than\ 5\ mils.$
- 4. Dimension L is measured in gauge plane.
- 5. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.

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